



Product/Process Change Notice - PCN 19_0275 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: LT4356-2 Notification of Die Revision Change

Publication Date: 15-Nov-2019

Effectivity Date: 17-Feb-2020 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:

Initial Release

Description Of Change:

Die changes were made to the LT4356-2 to ensure that the auxiliary amplifier functions properly during normal operation as well as in shutdown. The die changes fix the problem of the auxiliary amplifier failing to bias up if the part is powered up (voltage applied to the Vcc pin) while the SHDN# pin is held low (shutdown mode). The fixed silicon no longer requires the workaround of pulling the SHDN# pin high for more than 1ms to bias up the amplifier after the part is powered up.

Reason For Change:

The die change was made to address the issue with the auxiliary amplifier.

Impact of the change (positive or negative) on fit, form, function & reliability:

This change addresses the issue with the auxiliary amplifier, but otherwise has no impact on the fit, form, function and reliability. Product specifications are not affected by this change, and the datasheet remains unchanged.

Product Identification *(this section will describe how to identify the changed material)*

The new silicon can be identified with date code.

Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary.

Comments

Qualification has been performed per industry standard test methods. The changes were qualified by performing characterization over the full operating junction temperature range and through rigorous engineering evaluation across a broad range of application conditions. In addition, the revised die has successfully passed 1000 hours High Temperature Operating Life stress test.

Supporting Documents

Attachment 1: Type: Qualification Results Summary

ADI_PCN_19_0275_Rev_-_LT4356-2_Die_Change.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas:
PCN_Americas@analog.com

Europe:
PCN_Europe@analog.com

Japan:
PCN_Japan@analog.com

Rest of Asia:
PCN_ROA@analog.com

Appendix A - Affected ADI Models**Added Parts On This Revision - Product Family / Model Number (16)**

LT4356-1/LT4356CDE-2#PBF	LT4356-1/LT4356CDE-2#TRMPBF	LT4356-1/LT4356CDE-2#TRPBF	LT4356-1/LT4356CS-2#PBF	LT4356-1/LT4356CS-2#TRPBF
LT4356-1/LT4356HDE-2#PBF	LT4356-1/LT4356HDE-2#TRMPBF	LT4356-1/LT4356HDE-2#TRPBF	LT4356-1/LT4356HS-2#PBF	LT4356-1/LT4356HS-2#TRPBF
LT4356-1/LT4356IDE-2#PBF	LT4356-1/LT4356IDE-2#TRMPBF	LT4356-1/LT4356IDE-2#TRPBF	LT4356-1/LT4356IS-2#PBF	LT4356-1/LT4356IS-2#TRMPBF
LT4356-1/LT4356IS-2#TRPBF				

Appendix B - Revision History

Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	15-Nov-2019	17-Feb-2020	Initial Release

Analog Devices, Inc.

DocId:7903 Parent DocId:None Layout Rev:7